# onsemi

## Silicon Carbide (SiC) MOSFET – 160 mohm, 1200 V, M1, Bare Die NVC160N120SC1

## Description

Silicon Carbide (SiC) MOSFET uses a completely new technology that provide superior switching performance and higher reliability compared to Silicon. In addition, the low ON resistance and compact chip size ensure low capacitance and gate charge. Consequently, system benefits include highest efficiency, faster operation frequency, increased power density, reduced EMI, and reduced system size.

## Features

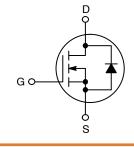
- $1200 \text{ V} @ \text{T}_{\text{J}} = 175^{\circ}\text{C}$
- Typ  $R_{DS(on)} = 160 \text{ m}\Omega$  at  $V_{GS} = 20 \text{ V}$ ,  $I_D = 10 \text{ A}$
- High Speed Switching with Low Capacitance
- 100% UIL Tested
- AEC-Q101 Qualified and PPAP Capable
- This Device is Halide Free and RoHS Compliant with exemption 7a, Pb–Free 2LI (on second level interconnection)

## Applications

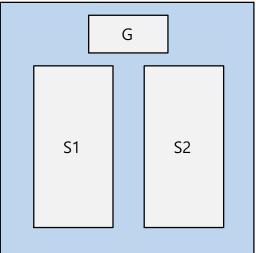
- Automotive Traction Inverter
- Automotive DC-DC Converter for EV/HEV

V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub> MAX	I <sub>D</sub> MAX
1200 V	224 mΩ @ 20 V	17 A

## **N-CHANNEL MOSFET**



#### DIE DIAGRAM



## **Die Information**

- Wafer Diameter
- 2,070 x 2,420 μm
- Metallization

Gate Pad Size

• Тор

Die Size

- Back
- Die Thickness
  - 600 x 330 μm

6 inch

Ti/TiN/Al

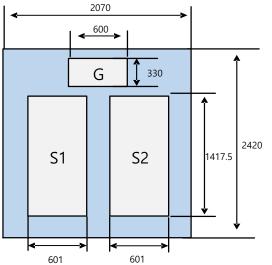
Typ. 200 μm

Ti/NiV/Ag

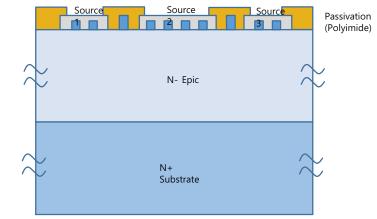
5 µm

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## **Die Layout**

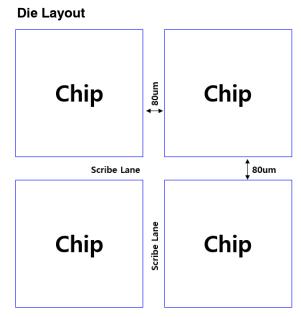


## **Die Cross Section**



## **Passivation Information**

- Passivation Material: Polymide (PSPI)
- Passivation Type: Local Passivation
- Passivation Thickness 10  $\mu$ m
  - : Passivation Area



## Figure 1. Bare Die Dimensions

#### MAXIMUM RATINGS (T<sub>C</sub> = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V <sub>DSS</sub>	1200	V
Gate-to-Source Voltage			V <sub>GS</sub>	-15/+25	V
Recommended Operation Values of Gate-to-Source Voltage	T <sub>C</sub> < 175°C		V <sub>GSop</sub>	-5/+20	V
Continuous Drain Current $R_{\theta JC}$	Steady State	$T_{\rm C} = 25^{\circ}{\rm C}$	۱ <sub>D</sub>	17	A
Power Dissipation $R_{\theta JC}$			PD	119	W
Continuous Drain Current $R_{\theta JC}$	Steady State	T <sub>C</sub> = 100°C	۱ <sub>D</sub>	12	A
Power Dissipation $R_{\theta JC}$			P <sub>D</sub>	59	W
Pulsed Drain Current (Note 2)	$T_{\rm C} = 25^{\circ}{\rm C}$		I <sub>DM</sub>	69	А
Single Pulse Surge Drain Current Capability	$T_{C}$ = 25°C, $t_{p}$ = 10 µs, $R_{G}$ = 4.7 $\Omega$		I <sub>DSC</sub>	140	А
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +175	°C
Source Current (Body Diode)			I <sub>S</sub>	11	А
Single Pulse Drain-to-Source Avalanche Energy ( $I_{L(pk)} = 16 \text{ A}, L = 1 \text{ mH}$ ) (Note 3)			E <sub>AS</sub>	128	mJ

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

## THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Note 1)	$R_{ heta JC}$	1.3	°C/W

1. The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.

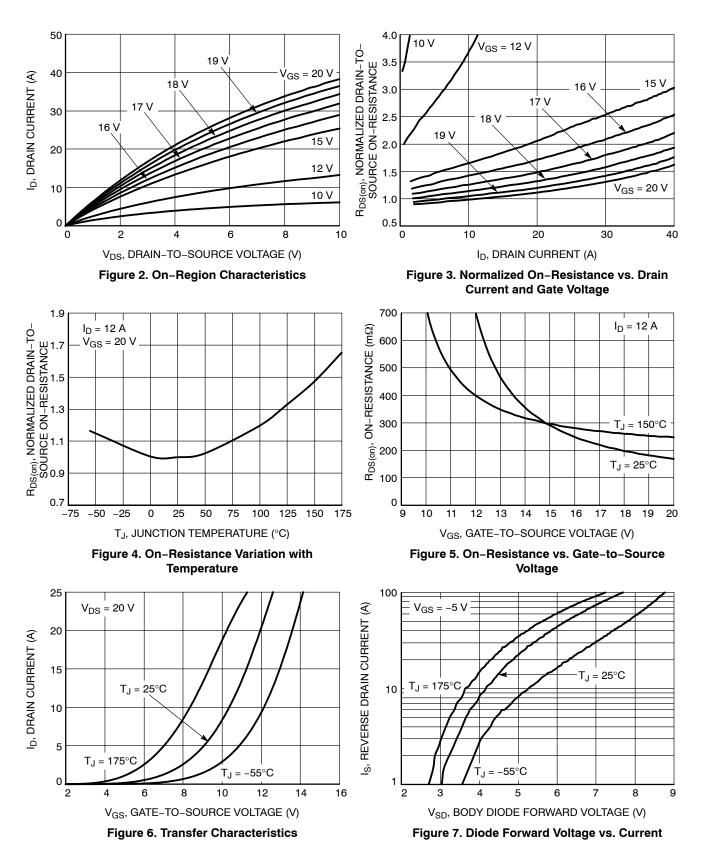
2. Repetitive rating, limited by max junction temperature. 3.  $E_{AS}$  of 128 mJ is based on starting  $T_J = 25^{\circ}C$ ; L = 1 mH,  $I_{AS} = 16$  A,  $V_{DD} = 120$  V,  $V_{GS} = 18$  V.

## **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = $25^{\circ}$ C unless otherwise stated)

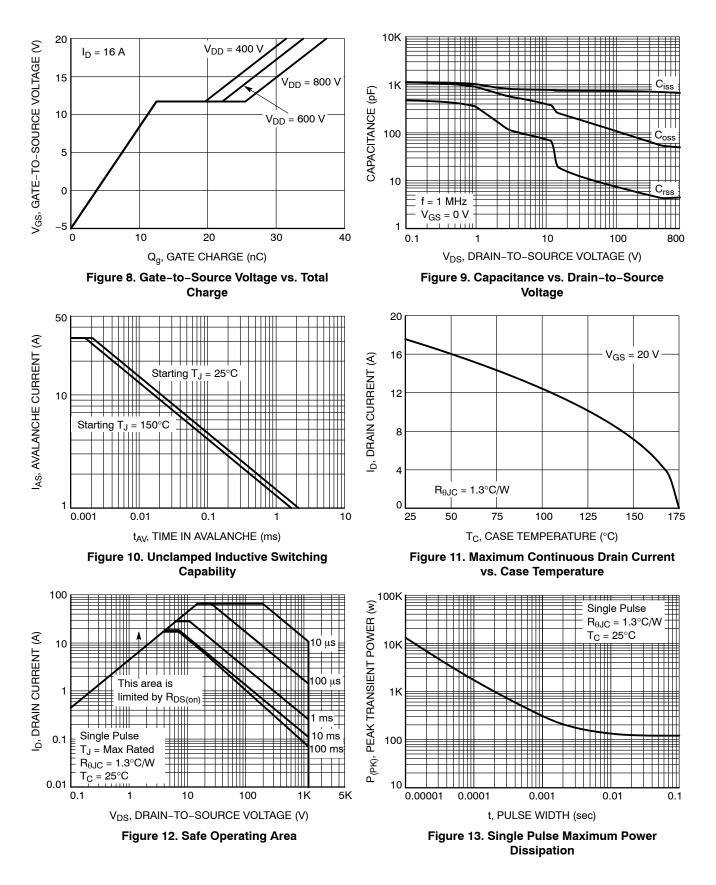
Parameter	Parameter Symbol Test Conditions		Min	Тур	Max	Unit	
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 1 mA	1200	-	-	V	
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /T <sub>J</sub>	$I_D = 1$ mA, referenced to $25^{\circ}C$	_	600	-	mV/°C	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS}$ = 0 V, $V_{DS}$ = 1200 V, $T_J$ = 25 $^\circ C$	-	_	100	μΑ	
		$V_{GS}$ = 0 V, $V_{DS}$ = 1200 V, $T_{J}$ = 175 °C	-	-	250		
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{GS}$ = +25/-15 V, $V_{DS}$ = 0 V	-	_	±1	μΑ	
ON CHARACTERISTICS							
Gate Threshold Voltage	V <sub>GS(th)</sub>	$V_{GS} = V_{DS}, I_{D} = 2.5 \text{ mA}$	1.8	3.1	4.3	V	
Recommended Gate Voltage	V <sub>GOP</sub>		-5	-	+20	V	
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	$V_{GS}$ = 20 V, $I_{D}$ = 12 A, $T_{J}$ = 25 °C	-	162	224	mΩ	
		$V_{GS}$ = 20 V, $I_{D}$ = 12 A, $T_{J}$ = 150°C	-	247	-		
Forward Transconductance	9 <sub>FS</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 12 A	-	3	-	S	
CHARGES, CAPACITANCES & GATE	RESISTANCE	•			•		
Input Capacitance	C <sub>ISS</sub>	$V_{GS} = 0 V, f = 1 MHz, V_{DS} = 800 V$	-	665	-	pF	
Output Capacitance	C <sub>OSS</sub>	1	-	50	-		
Reverse Transfer Capacitance	C <sub>RSS</sub>	1	-	5	-		
Total Gate Charge	Q <sub>G(tot)</sub>	$V_{GS} = -5/20$ V, $V_{DS} = 600$ V, $I_D = 16$ A	-	34	-	nC	
Threshold Gate Charge	Q <sub>G(th)</sub>		-	6	-	-	
Gate-to-Source Charge	Q <sub>GS</sub>		_	12.5	-		
Gate-to-Drain Charge	Q <sub>GD</sub>		_	9.6	-		
Gate Resistance	R <sub>G</sub>	f = 1 MHz	_	1.4	-	Ω	
SWITCHING CHARACTERISTICS		•		1			
Turn-On Delay Time $t_{d(on)}$ $V_{GS} = -5/20 \text{ V}, \text{ V}_{DS} = 800 \text{ V},$				11	-	ns	
Rise Time	t <sub>r</sub>	$I_D = 16 A, R_G = 6 \Omega,$ Inductive Load	-	19	-	-	
Turn-Off Delay Time	t <sub>d(off)</sub>		-	15	-		
Fall Time	t <sub>f</sub>		-	8	-		
Turn-On Switching Loss	E <sub>ON</sub>		-	200	-	μJ	
Turn-Off Switching Loss	E <sub>OFF</sub>		-	34	-		
Total Switching Loss	E <sub>TOT</sub>		-	234	-		
DRAIN-SOURCE DIODE CHARACTER	RISTICS	•		1		4	
Continuous Drain-to-Source Diode Forward Current	I <sub>SD</sub>	$V_{GS} = -5 V$	_	-	11	А	
Pulsed Drain-to-Source Diode Forward Current (Note 2)	I <sub>SDM</sub>	V <sub>GS</sub> = -5 V	-	-	69	А	
Forward Diode Voltage	V <sub>SD</sub>	$V_{GS} = -5 \text{ V}, \text{ I}_{SD} = 6 \text{ A}$	-	4	10	V	
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = -5/20$ V, $I_{SD} = 16$ A,	-	15	-	ns	
Reverse Recovery Charge	Q <sub>RR</sub>	dI <sub>S</sub> /dt = 1000 A/µs	-	45	-	nC	
Reverse Recovery Energy	E <sub>REC</sub>	1	_	3.9	_	μJ	
Peak Reverse Recovery Current	I <sub>RRM</sub>	1	_	6.2	-	А	
Charge Time	Та	1	_	7.4	_	ns	
Discharge Time	Tb	1	_	7	_	ns	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

## TYPICAL CHARACTERISTICS (T<sub>J</sub> = 25°C unless otherwise noted)



#### TYPICAL CHARACTERISTICS (T<sub>J</sub> = 25°C unless otherwise noted) (continued)



**TYPICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise noted) (continued)

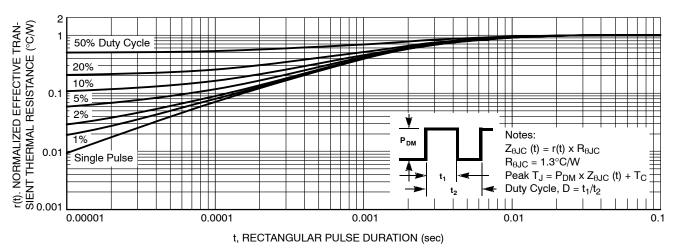


Figure 14. Junction-to-Ambient Thermal Response

## **ORDERING INFORMATION AND PACKAGE MARKING**

Orderable Part Number	Top Marking	Package	Packing Method	Reel Size	Tape Width	Quantity
NVC160N120SC1	N/A	Die	Wafer	N/A	N/A	N/A

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